

Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)	<table border="1" style="width: 100%; border-collapse: collapse;"> <tr> <td style="width: 50%;">ATTY DOCKET NO. 0378-0386P</td> <td style="width: 50%;">APPLICATION NO. NEW</td> </tr> <tr> <td colspan="2">APPLICANT KUWAYAMA, Akiko</td> </tr> <tr> <td>PILING DATE February 28, 2002</td> <td>GROUP 2615</td> </tr> </table>	ATTY DOCKET NO. 0378-0386P	APPLICATION NO. NEW	APPLICANT KUWAYAMA, Akiko		PILING DATE February 28, 2002	GROUP 2615
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 10/08/02
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 U.S. PTO

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
						YES	NO
as	2000-115624	2000-04-21	JP			ABS	
as	2000-147623	2000-05-26	JP			ABS	

OTHER DOCUMENTS (Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.)

as	Seto et al, "Activities for Standardization of Test and Evaluation of Biometrics Authentication Technologies in Japan" The Journal of the Institute of Electronics, Information and Communication Engineers, Vol. 83, No.8, pp. 624-629 (2000).
as	Shinozaki, "Fingerprint Sensor Challenging a Taboo of Semiconductor", CX-PAL Sony Semiconductor News, Vol. 41, pp. 24-25 (1999).

EXAMINER	DATE CONSIDERED 2/9/05
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